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FORM PTO-1449 U.S. Department of Commerce (Rev. 4/92) Patent and Trademark Office

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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U.S. PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Process Focus SEMICONDUCTOR WORLD 1998 pgs. 74-76 and translation(Improving Resistance to Heat and O2 Plasma is the Key to Successfully Applying Films to the Cu-Damascene Process, by Kawane, Editor of Semiconductor World pgs1-7)

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